

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1896SERIAL NO.  
10/050,373LIST OF REFERENCES BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Gurtej S. Sandhu, et al.

FILING DATE  
January 15, 2002GROUP  
2813

## U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Xu</i>	AA	3,627,598	12/1971	McDonald, et al.			
<i>Xu</i>	AB	4,254,161	03/1981	Kemlage			
<i>Xu</i>	AC	4,262,631	04/1981	Kubacki			
<i>Xu</i>	AD	4,435,447	03/1984	Ito, et al.			
<i>Xu</i>	AE	4,882,649	11/1989	Chen, et al.			
<i>Xu</i>	AF	4,891,684	01/1990	Nishioka, et al			
<i>Xu</i>	AG	4,980,307	12/1990	Ito, et al.			
<i>Xu</i>	AH	4,996,081	02/1991	Ellul, et al.			
<i>Xu</i>	AI	5,051,794	09/1991	Mori			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>Xu</i>	AJ	EP 0886308 A2	12/1998	Europe				
<i>Xu</i>	AK	237243 a	04/2001	Japan (ASM America, Inc.)				
	AL							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>Xu</i>	AM		Wolf, Stanley, "Silicon Processing for the VLSI Era, Volume 3: The Submicron Mosfet", Lattice Press, 1995, pages 648-9.
			Laughery, et al, "Effect of H <sub>2</sub> Content on Reliability of Ultrathin <i>In-Situ</i> Steam Generated (ISSG) SiO <sub>2</sub> , EEE Electron Device Letters, September, 2000, Volume 21, No. 9.
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*Wooja Schuler*

DATE CONSIDERED

*11/05/05*

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He	AA	5,142,438	08/1992	Reinberg, et al.			
He	AB	5,227,651	07/1993	Kim, et al.			
He	AC	5,237,188	08/1993	Iwai, et al.			
He	AD	5,324,679	06/1994	Kim, et al.			
He	AE	5,330,936	07/1994	Ishitani			
He	AF	5,350,707	09/1994	Ko, et al.			
He	AG	5,376,593	12/1994	Sandhu, et al.			
He	AH	5,393,702	02/1995	Yang, et al.			
He	AI	5,397,748	03/1995	Watanabe, et al.			

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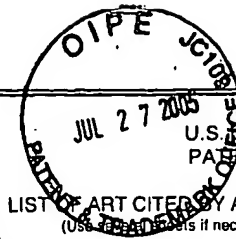
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<i>He</i>	AA	5,398,641	03/1995	Shih			
	AB	5,459,105	10/1995	Matsuura			
	AC	5,498,890	03/1996	Kim, et al.			
	AD	5,504,029	04/1996	Murata, et al.			
	AE	5,508,542	04/1996	Geiss, et al.			
	AF	5,523,596	06/1996	Ohi, et al.			
	AG	5,731,235	03/1998	Srinivasan, et al.			
	AH	5,821,142	10/1998	Sung, et al.			
<i>He</i>	AI	5,844,771	12/1998	Graettinger, et al.			

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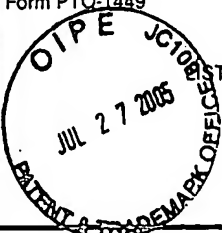



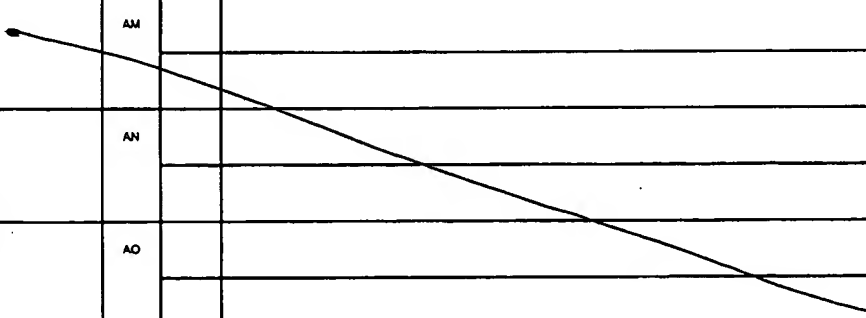
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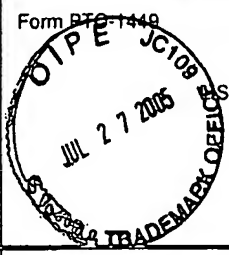
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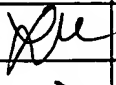
  

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	AA	5,851,603	12/1998	Tsai, et al.			
	AB	5,882,978	03/1999	Srinivasan, et al.			
	AC	6,001,741	12/1999	Alers			
	AD	6,001,748	12/1999	Tanaka			
	AE	6,008,104	12/1999	Schrems			
	AF	6,051,865	04/2000	Gardner, et al.			
	AG	6,063,713	06/2000	Doan			
	AH	6,077,754	06/2000	Srinivasan, et al.			
	AI	6,090,597	08/2000	Tsu, et al.			
FOREIGN PATENT DOCUMENTS							
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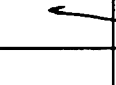
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<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
  	AB	6,111,744	08/2000	Doan				
	AC	6,168,980	01/2001	Yamazaki, et al.				
	AD	6,207,985 B1	03/2001	Walker				
	AE	6,323,138 B1	11/2001	Doan				
	AF	6,348,420 B1	02/2002	Raaijmakers, et al.				
	AG	6,265,327	07/2001	Kobayashi, et al.				
	AH	6,350,707 B1	02/2002	Liu, et al.				
	AI	6,723,599 B2	04/2004	Eppich, et al.				
		6,893,981 B2	05/2005	Park, et al.				
<b>FOREIGN PATENT DOCUMENTS</b>								
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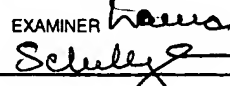
  

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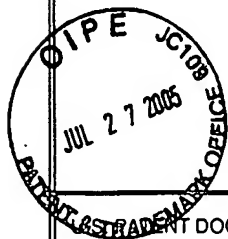
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<i>He</i>	AA	2001/0036752	11/2001	DeBoer, et al.			
<i>J</i>	AB	2002/0009861	08/1998	Narwankar, et al.			
<i>J</i>	AC	2002/0052124	05/2002	Raaijmakers, et al.			
<i>He</i>	AD	2003/0034518A1	02/2003	Yoshikawa			
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